

Discussion

Driver in 2003:

Started to see confusion in testing protocols of
PCB motherboards vs package substrates

Motherboards > Package > MCM > SIP ?

2002/2003 IPC roadmap included tables of

- Test conditions
- Performance requirements

IPC specs, JEDEC, Auto, Military

- In light of the rapidly changing technology environment and new developing markets appearing, in your opinion is the industry properly focused on reliability and reliability protocols??
- Taken as a group, is there something different the trade organizations and consortia could do to improve the situation??

Test Type	Index	Title	Conditions	Uses	Comments
A) T&H (Moisture and delamination sensitivity)	A-1 (IPC)	<u>IPC-TM-650 2.6.16</u> Pressure vessel method for glass epoxy laminates integrity	15psi /30 min + Solder dip	PWB slugs	Still widely used laminates test except: PCT times > 15 minutes and sample thicknesses > 1/16" are common today.
	A-2 (IPC)	<u>IPC-TM-650 2.6.2.1A</u> Water absorption, metal clad plastic laminates	24 hrs in H2O at 23C (prebake: 1 hr at 105-110C)	PWB slugs	Standard for Laminates weight gain (relative moisture absorption measurement).
	A-3 (Jedec/ IPC)	<u>JSTD-020C</u> Moisture/Reflow Sensitivity Classification for Non- hermetic Solid State Surface Mount Devices	Varies per Levels 1 – 6: Soak 30C/60% to 85C/85% 3x reflow, 225, 245, 250, or 260C (standard reflow to Pb free).	Componen ts	Widely used for components to determine moisture level for assembly ("popcorn" mechanism), and as precon before other tests.
	A-4	<u>JESD220-A102C</u> Accelerated Moisture Resistance-- Unbiased Autclave	1210C / 100%RH (A)24 – (F)336 hrs, +Electrical test	Componen ts	Pure moisture resistance (no solder dip or reflow).
	A-5	<u>JESD220-A118</u> Accelerated Moisture Resistance-- Unbiased HAST	130C / 85%RH, 1100C / 85%RH 96 – 264 hrs	Componen ts	Pure moisture resistance (no solder dip or reflow).

Aerospace Issues

Unique to Aerospace:

- Long service lifetimes
- Rugged operating environments
- High consequences of failure
- Repair at circuit card level (mixed alloys)
- Quantify reliability at design
- Strict configuration control requirements (obsolescence)



Beyond Aerospace Control (most of the time):

- Alloys on part terminations
- Alloys on printed wiring pad finishes
- Reliability tests conducted by suppliers cannot be assumed to assure reliability in aerospace applications

Major Aerospace Technical Issues (From an AIA Position Paper, January 2007)

- Specific aerospace risks:
 - (1) unproven reliability of solder joints
 - (2) degraded reliability due to “tin whiskers,”
 - (3) loss of configuration control
 - (4) impaired reparability
- Most urgent needs:
 - (1) methods to analyze, test and qualify lead-free electronics for aerospace applications;
 - (2) methods to assess and quantify effects of lead-free electronics in aerospace system safety and certification analyses;
 - (3) better understanding of the causes and mitigation methods for tin whiskers; and
 - (4) better understanding of the reliability of lead-free solder joints especially those associated with surface mount area array packages.

Technical Issues (GEIA-STD-0005-3)

Operating environments

Steady state temperature (max, min, average)

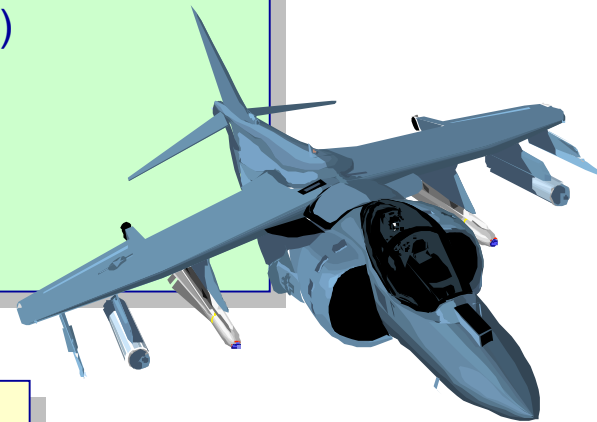
Temperature cycling (upper and lower limits, ramp rates, dwell times)

Vibration (sine, swept sign, random, coherent-incoherent)

Mechanical shock

Combined environments

Duty cycles



Material properties of solder alloys and alloy mixtures

Tensile strength

Creep properties

Young's modulus

Poisson's ratio

Yield points

Etc.

How do they vary with temperature?

Acceleration models

Thermal cycling

Steady state
temperature

Vibration

Summary

- The Markets are changing
- The Products are changing
- Failure Modes are changing
- Risks are changing
- Reliability Standards must:
 - Address the expectations of the Customer
 - Reduce the risk of the OEM
 - Reduce the risks throughout the supply chain
- Reliability Test Methodologies must:
 - Be correlated with known failure modes
 - Minimize real risks throughout the supply chain.
 - Be Risk-Benefit effective
 - Provide quick response
- To succeed we must prioritize and focus our efforts
- We Need a Major Change in our Methodologies

- Put in place a feedback system for reporting on failure modes. SIP project from iNEMI, (iNEMI volunteer to collect)
 - What is in it for reporting companies?
- Develop a guidelines for reliability testing but targeted a market segment
- Increase spec harmony
- Harmonization of whisker dox? GEIA, JEDEC, IPC, Japan work to IEC

- Push for case studies. No more widget testing
- Modeling with data sets
- Hot topic copper erosion?
 - What data is being collected
- Clearing house of reliability efforts (promo)
 - Standards, test programs (thermal, vibe shock), modeling, data sets (contact list)
- Vibration and shock needs
- Rework

- Press fit and LF?
- Fretting corrosion
- Hi speed/Hi frequency event detection
- Lead free for dummies (beyond solders)
- Reliability for dummies
- Cookbook DFR